

MPS150

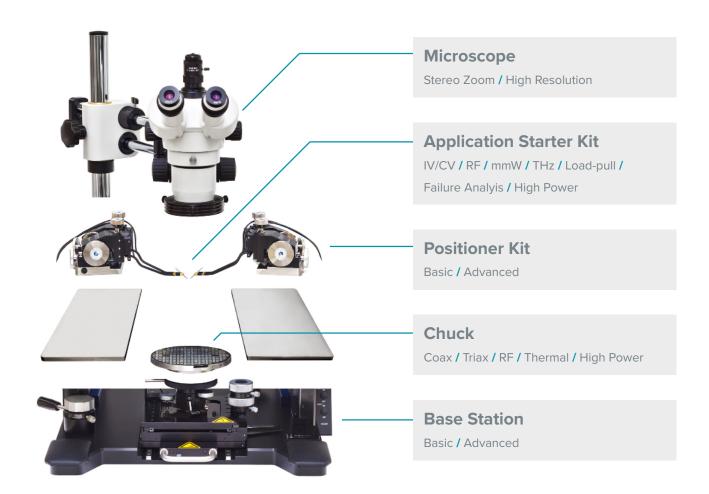
150 mm Modular Probe Station

Customize your 150 mm probe station based on flexible modules at an incredible price!

FormFactor introduces a new modular concept for its best-inclass 150 mm probe stations. This will make it even easier to configure your individual probe solution for current and future needs at an incredible price. Simply choose a base station and add as many application-specific starter kits as you need.



Example: Complete 150 mm Entry-level IV/CV Manual Probe Station



^{*} Price includes: 150 mm station, coaxial chuck, stereo zoom microscope, 4 DC positioners and probe tips. Excludes shipping and installation.

Configuration Examples



Coax

DC parametric test down to pA levels

- / Movable platen with 40 mm height adjustment, 200 μ m contact / separation stroke and \pm 1 μ m repeatability
- / Chuck stage with adjustable friction & stage lock, unique Z chuck adjustment and 90 mm pull-out
- / Magnetic positioners with 1 μ m feature resolution and 3 linear axes with precision ball bearing



Triax

Low-noise measurements down to fA level

- / Stereo microscope: 15x-100x magnification with large field-of-view and camera-ready c-mount
- / Four triax probe arms and high-quality triax cables
- / Light/EMI shielding (optional)
- / Upgrade option for fF-level measurements
- / TRIAX chuck with ± 8 fine theta chuck rotation, three auxiliary areas, chuck surface with $\pm 5~\mu m$ planarity for consistent contact force and overtravel
- / East/West to North/South measurements with single setup

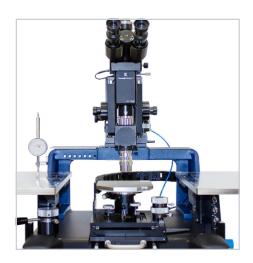


RF test up to 67 GHz

- / Three probe technologies available: Infinity Probe, ACP Probe, IZI Probe
- / Matching cables and substrates included
- / RF chuck ±3 μm surface planarity
- / Unique 200 μ m platen contact/ separation stroke with \leq ± 1 μ m accuracy for repeatable contact
- / WinCal XE Calibration Software



Configuration Examples (continued)



mmW - 70 GHz through sub-THz and load-pull

70 GHz through sub-THz and load-pull

- / SlimVue microscope with quick lens exchange, 1 μ m opitcal resolution, resolving <50 μ m pads
- / Engraved guides on mmW platen for application-specific SIGMA Kits
- Supports broadband, load pull, coax RF and banded waveguide configuration
- / Optical feedback on platen position (gauge)
- / Vibration Isolation Platform



mmW probing up to THz and load-pull

- / SlimVue microscope with quick lens exchange, 1 μm opitcal resolution, resolving <50 μm pads
- / Engraved guides on mmW platen for application-specific SIGMA Kits
- Supports broadband, load pull, coax RF and banded waveguide configuration
- / Optical feedback on platen position (gauge)
- / Rock-solid mechanical design and vibration isolation platform
- / Submicron stage accuracy
- / Motorized positioners
- / <+-1 μm separation repeatability
- / Micrometer-accuracy and repeatable probe placement and over travel

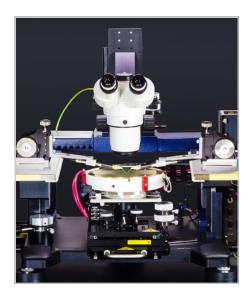


Failure analysis and design debug

- Stable microscope bridge design and XY microscope with up to 4000x magnification (option)
- / Laser cutter and camera ready
- / Contact submicron features
- / Simultaneous use of probe card and single needles (option)
- / Chuck ready for single DUT
- / Quickest transition from wafer-to-chip-to-package
- / Vacuum positioners with 1 µm feature resolution
- / DPP450 positioner with nanometer resolution and accuracy (option)



Configuration Examples (continued)



High Power

On-wafer power device characterization

- / Multi-purpose SIGMA instrument integration kit
- / Triax probe with protected guard
- / Seamless integration of various analyzers
- Triax chuck with surface coating for low-leakage measurements up to 3 kV, high-isolation ready
- / High-current measurements up to 100 A with lowest contact resistance
- / Optional upgrade for 10 kV (coax) operating voltage
- / Thin wafer handling capability
- / Arcing protection and advanced grounding concept
- / Shield Enclosure with interlock for EMI/light-tight environment
- / Maximum protection from high-voltage shock for users and devices

Educational Savings Program

Make the Most of Your Research Budget

With our Education Savings Program you can benefit from exclusive savings on 150 mm wafer probe systems.

Program Benefits*

- / Free shipping
- / 2-Year Factory Warranty
- / 4 Years of Free WinCal XE™ Calibration Software Updates
- / 10% Discount on Upgrades



*For terms and conditions, please contact your local sales representative or visit us at https://www.formfactor.com/download/educational-savings-program/

